

Special Issue

EUV and X-ray Wavefront Sensing

Message from the Guest Editors

The aim of this Special Issue is to collect the most recent works of world-recognized researchers, active in the study, development, calibration, and characterization of EUV (extreme ultraviolet) and X-ray wavefront sensors or wavefront techniques that are applied in at-wavelength metrology, aimed to achieve the highest accuracy and, thus, the lowest uncertainty. We cordially invite you to share your work, expertise, and insights with the dimensional measurement and calibration community, in the form of research articles and reviews.

Guest Editors

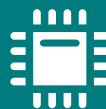
Dr. Mourad Idir

Dr. Daniele Cocco

Dr. Lei Huang

Deadline for manuscript submissions

closed (31 October 2021)



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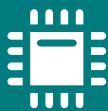
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Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. *Sensors* organizes Special Issues devoted to specific sensing areas and applications each year.

Editor-in-Chief

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